

Harmonized system of quality assessment for electronic components — Sectional specification: Interface monolithic integrated circuits

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Committees responsible for this British Standard

The preparation of this British Standard was entrusted by the Electronic Components Standards Committee (ECL/-) to Technical Committee ECL/17 upon which the following bodies were represented:

- British Broadcasting Corporation
- British Telecommunications plc
- British Equipment Trade Association
- Electronic Components Industry Federation
- Electronic Engineering Association
- National Supervising Inspectorate
- Society of British Aerospace Companies Limited
- Telecommunication Engineering and Manufacturing Association (TEMA)

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National foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Committee. It is identical with CENELEC Electronic Components Committee (CECC) 90300:1987 “*Harmonized system of quality assessment for electronic components. Sectional specification: Interface monolithic integrated circuits*” as amended by Amendment No. 1 published in 1994. It supersedes BS CECC 90300:1985, which is withdrawn. It should be noted that the withdrawal of BS CECC 90300:1985 does not affect the validity of approvals which make reference to that standard.

This standard gives the terminology, quality assessment procedures, test and measurement procedures applicable to the sub-family of interface monolithic integrated circuits. It also includes the common blank detail specification for interface monolithic integrated circuits.

This standard is a harmonized specification within the CECC system and should be read in conjunction with BS CECC 90000.

This standard specifies the use of substances and/or test procedures that may be injurious to health if adequate precautions are not taken. It refers only to technical suitability and in no way absolves either the supplier or the user from statutory obligations relating to health and safety at any stage of manufacture or use.

The British Standards Institution’s prescribed layout for a harmonized detail specification will in due course be incorporated in the revised BS 9000-1:1981, by amendment.

This second issue of BS CECC 90300 results from amendments and additions which have been agreed since the first issue was published in 1985.

Terminology and conventions. The text of the CECC specification has been approved as suitable for publication as a British Standard without deviation. Some terminology and certain conventions are not identical with those used in British Standards; attention is drawn especially to the following.

The comma has been used as a decimal marker. In British Standards it is current practice to use a full point on the baseline as the decimal marker.

Cross-references

International Standard	Corresponding British Standard
IEC 68-2-30:1980	BS 2011 <i>Basic environmental testing procedures</i> Part 2.1Db:1981 <i>Test Db and guidance. Damp heat cyclic (12 + 12 hour cycle)</i> (Identical)
IEC 148:1969	BS 3363:1980 <i>Specification for letter symbols for semiconductor devices and integrated microcircuits</i> (Identical)
IEC 617-12:1983	BS 3939 <i>Guide for graphical symbols for electrical power, telecommunications and electronics diagrams</i> Part 12:1985 <i>Binary logic elements</i> (Identical)
IEC 747-1:1983	BS 6493 <i>Semiconductor devices: discrete devices and integrated circuits</i> Part 1 <i>Discrete devices</i> Section 1.1:1984 <i>General</i> (Identical)

International Standard	Corresponding British Standard
IEC 747-10:1984	BS 9970 <i>Harmonized system of quality assessment for electronic components. Semiconductor devices</i> Part 0:1985 <i>Generic specification</i> (Identical) BS 6493 <i>Semiconductor devices: discrete devices and integrated circuits</i> Part 2 <i>Integrated circuits</i>
IEC 748-1:1984	Section 2.1:1985 <i>General</i> (Identical)
IEC 748-2:1985	Section 2.2:1986 <i>Recommendations for digital integrated circuits</i> (Identical)
IEC 748-3:1986	Section 2.3:1987 <i>Recommendations for analogue integrated circuits</i> (Identical)
CECC 90000:1985	BS CECC 90000:1985 <i>Harmonized system of quality assessment for electronic components. Generic specification: Monolithic integrated circuits</i> (Identical)
CECC 90100:1986	BS CECC 90100:1986 <i>Harmonized system of quality assessment for electronic components. Sectional specification: Digital monolithic integrated circuits</i> (Identical)
CECC 90200:1983	BS CECC 90200:1983 <i>Harmonized system of quality assessment for electronic components. Sectional specification: Analogue integrated circuits</i> (Identical)
IEC 748-4 "Interface integrated circuits", to which reference is made in the text, has not yet been published.	

A British Standard does not purport to include all the necessary provisions of a contract. Users of British Standards are responsible for their correct application.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

Summary of pages

This document comprises a front cover, an inside front cover, pages i to iv, the CECC title page, pages ii to iv, pages 1 to 14, an inside back cover and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

English version

Harmonized System of Quality Assessment for
Electronic Components

SECTIONAL SPECIFICATION:
**INTERFACE MONOLITHIC
INTEGRATED CIRCUITS**

Système Harmonisé d'Assurance de la Qualité
des Composants Electroniques

SPEZIFICATION INTERMEDIAIRE:
**CIRCUITS INTEGRES
MONOLITHIQUES
D'INTERFACE**

Harmonisiertes Gütebestätigungssystem für
Baulemente der Elektronik

RAHMENSPEZIFIKATION:
**INTEGRIERTE
ANPASSUNGS-
SCHALTUNGEN**



2 Issue
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Ausgabe

CECC 90 300

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